

## Jasco FT/IR X Series Key Advantages & Benefits



FT/IR-4X Research-grade model



FT/IR-6X/8X High-end model

The JASCO FTIR-X Series is an advanced IR spectroscopy instrument designed for scientists who require precise and reliable results. With high-resolution detectors and customizable measurement options, it is ideal for a wide range of applications from materials science to pharmaceuticals. Each model in the series has unique features and specifications that lead to exceptional performance.

With the JASCO FTIR-X Series, you can expect to achieve accurate and precise results every time you use it. Whether you work in a university lab, government research facility, or private company, the Jasco FTIR is the perfect tool for your research needs.

The **Spectra Manager software** package is used across all spectroscopy instrumentation, thus familiarity with one instrument provides familiarity with the entire range. The durable construction and easy maintenance of the JASCO FTIR makes it a smart investment for any laboratory.

### Features, Advantages and Benefits at a glance

Features	Advantages	Benefits
High sensitivity detector	Quick and accurate detection	More accurate analysis of samples
Intuitive user interface	Easy to use	Saves time and reduces the need for training
Automatic alignment	Saves time and reduces errors	Improves efficiency and accuracy
High resolution	Ability to distinguish closely spaced spectral features	More detailed information about the sample
Multiple sampling options	Versatile analysis	Allows for a variety of sample types to be analysed
Large sample compartment	Can accommodate larger samples	More flexibility in the types of samples that can be analysed
High signal-to-noise ratio	Improved accuracy and precision	Provides more reliable results
High-speed scanning	Rapid analysis	Saves time and increases efficiency
Flexible connectivity options	Easy data transfer	Makes it easy to integrate into existing workflows
Advanced software capabilities	Robust data analysis tools	Enables more in-depth analysis of samples